



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AO3421E**

**30V P-Channel MOSFET**

### General Description

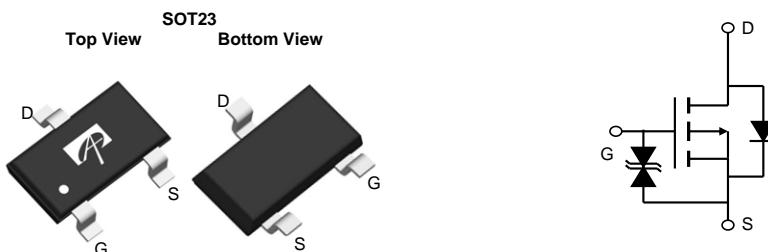
The AO3421E combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

### Product Summary

$V_{DS}$	-30V
$I_D$ (at $V_{GS}=-10V$ )	-3A
$R_{DS(ON)}$ (at $V_{GS}=-10V$ )	< 95mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 160mΩ

### Typical ESD protection

HBM Class 2



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-3	A
$T_A=70^\circ C$		-2	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-18	
Power Dissipation <sup>B</sup>	$P_D$	1.4	W
$T_A=70^\circ C$		0.9	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	70	90	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		100	125	°C/W
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	63	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm16\text{V}$			$\pm10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.4	-2	-2.5	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-18			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-3\text{A}$ $T_J=125^\circ\text{C}$	78	95		$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$	112	135	120	
$g_{FS}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-3\text{A}$	6			S
$V_{SD}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-0.8	-1		V
$I_S$	Maximum Body-Diode Continuous Current				-1.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		215		pF
$C_{oss}$	Output Capacitance			46.5		pF
$C_{rss}$	Reverse Transfer Capacitance			27.5		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		9.5	19	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-3\text{A}$		4.6	8	nC
$Q_g(4.5\text{V})$	Total Gate Charge			2.2	4	nC
$Q_{gs}$	Gate Source Charge			0.85		nC
$Q_{gd}$	Gate Drain Charge			1.2		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=5\Omega, R_{\text{GEN}}=3\Omega$		8		ns
$t_r$	Turn-On Rise Time			4		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			13.5		ns
$t_f$	Turn-Off Fall Time			4		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-3\text{A}, dI/dt=500\text{A}/\mu\text{s}$		9		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-3\text{A}, dI/dt=500\text{A}/\mu\text{s}$		16		nC

A. The value of  $R_{iJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

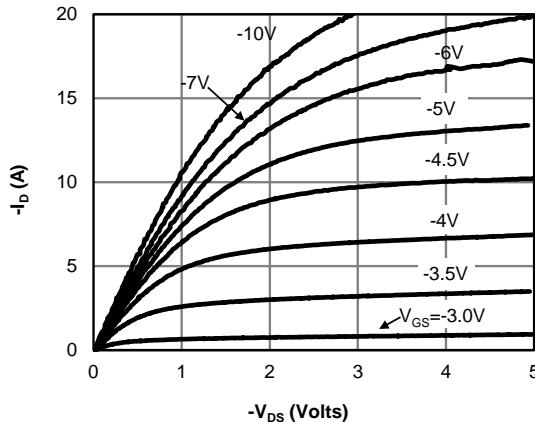
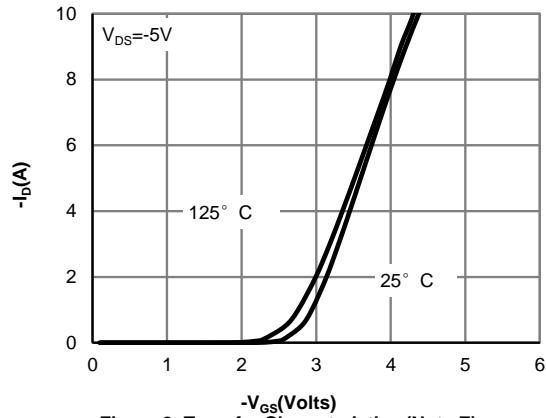
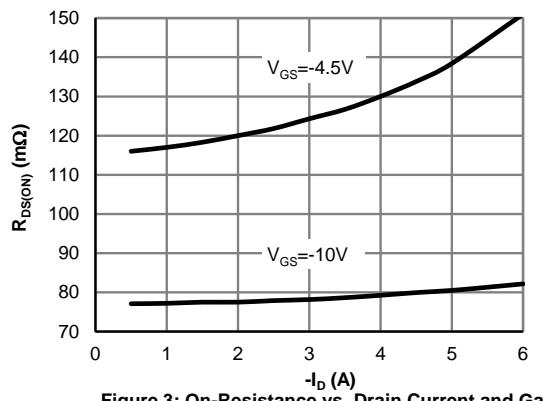
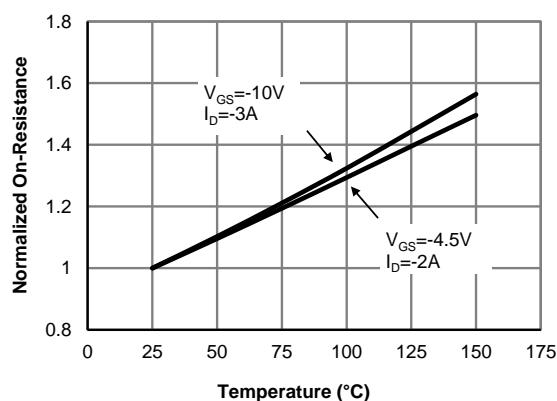
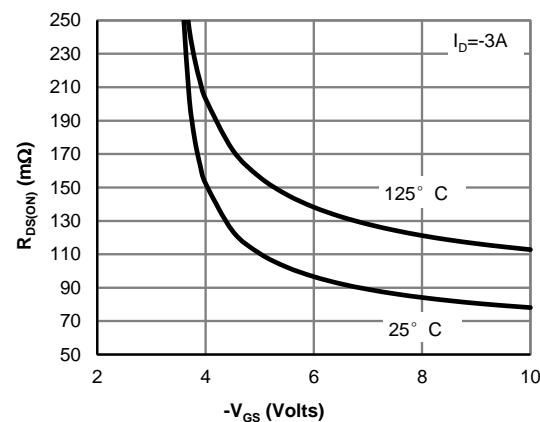
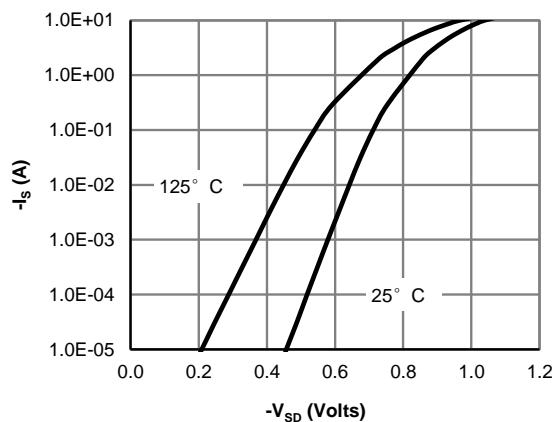
D. The  $R_{iJA}$  is the sum of the thermal impedance from junction to lead  $R_{iJL}$  and lead to ambient.

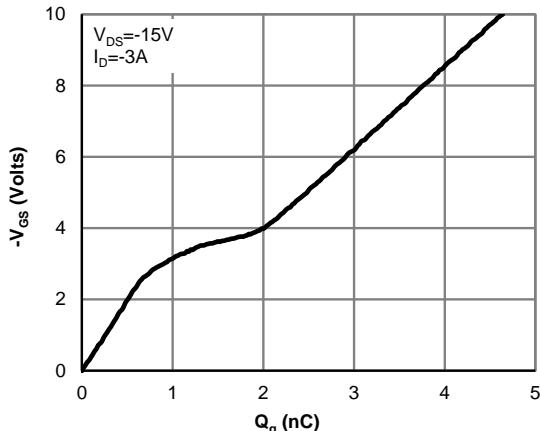
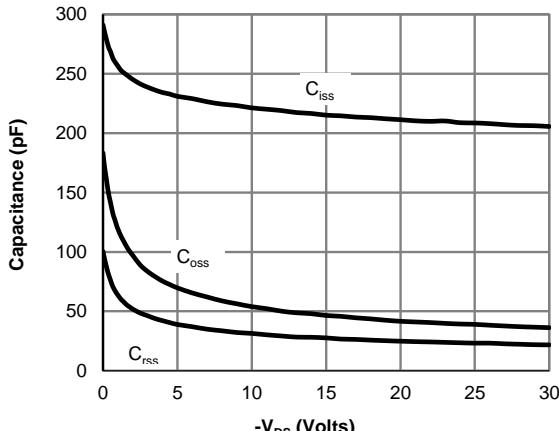
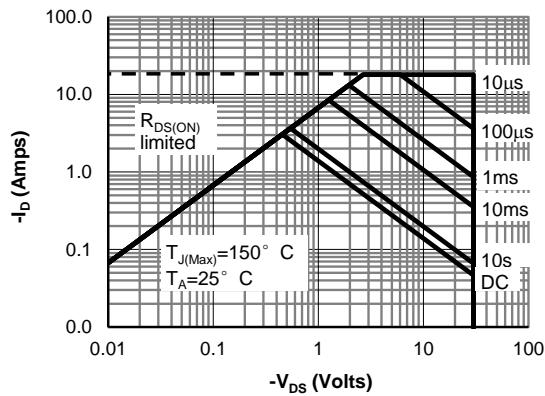
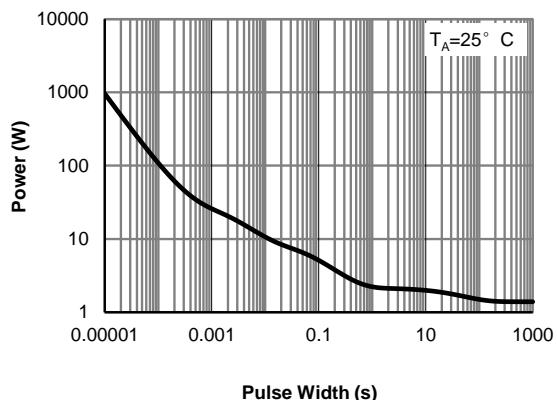
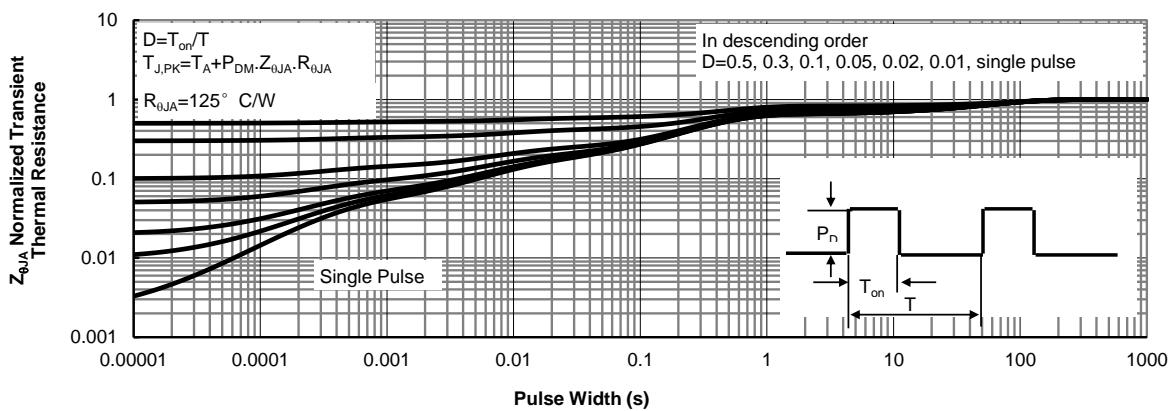
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

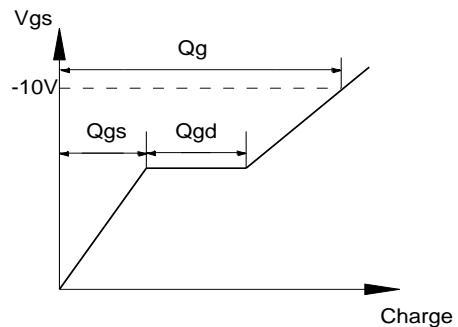
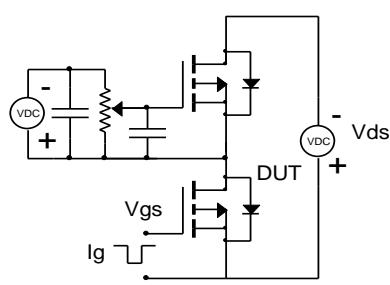
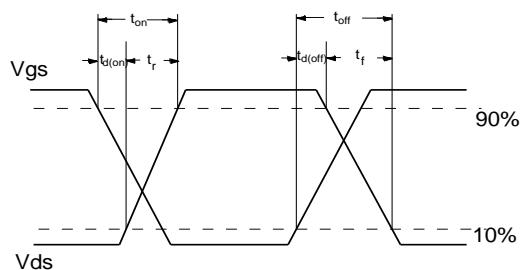
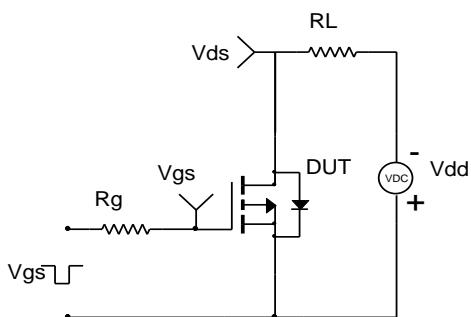
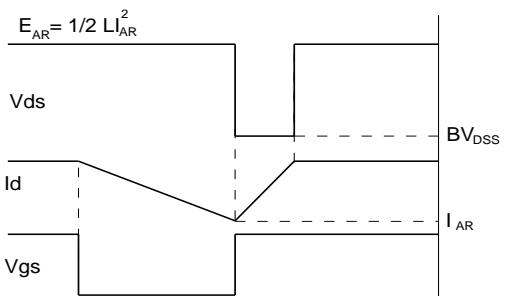
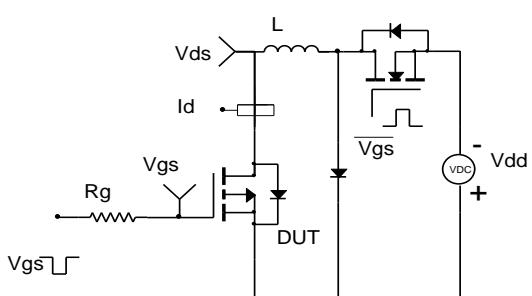
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
